

Table 1. Fractional atomic coordinates and equivalent isotropic displacement parameters (Å²)
$$U_{eq} = (1/3)\sum_i \sum_j U_{ij} a_i^* a_j^* \mathbf{a}_i \cdot \mathbf{a}_j$$

	x	y	z	U _{eq}
Mo	0.746823 (13)	0.15256 (2)	0.106914 (10)	0.01862 (8)
N1	0.68030 (13)	0.3970 (2)	0.03812 (10)	0.0185 (3)
N2	0.85932 (14)	0.1726 (2)	0.01384 (11)	0.0204 (4)
O1	0.62936 (11)	0.0997 (2)	0.00005 (9)	0.0237 (3)
O2	0.87571 (11)	0.2691 (2)	0.17166 (9)	0.0228 (3)
O3	0.78954 (13)	-0.0384 (2)	0.12405 (10)	0.0284 (4)
O4	0.68206 (12)	0.1876 (2)	0.17916 (10)	0.0276 (3)
C1	0.5771 (2)	0.2072 (3)	-0.05969 (13)	0.0217 (4)
C2	0.4984 (2)	0.1664 (3)	-0.13632 (14)	0.0274 (5)
C3	0.4472 (2)	0.2864 (3)	-0.19557 (14)	0.0316 (5)
C4	0.4707 (2)	0.4421 (3)	-0.17812 (14)	0.0299 (5)
C5	0.5494 (2)	0.4872 (3)	-0.09871 (13)	0.0233 (4)
C6	0.5746 (2)	0.6437 (3)	-0.07057 (15)	0.0258 (5)
C7	0.6469 (2)	0.6727 (3)	0.00931 (15)	0.0242 (4)
C8	0.6996 (2)	0.5466 (2)	0.06402 (13)	0.0203 (4)
C9	0.6038 (2)	0.3676 (2)	-0.04086 (13)	0.0202 (4)
C10	0.7764 (2)	0.5817 (3)	0.15304 (14)	0.0255 (5)
C11	0.9569 (2)	0.3074 (3)	0.14243 (13)	0.0222 (4)
C12	1.0443 (2)	0.3932 (3)	0.19175 (15)	0.0283 (5)
C13	1.1273 (2)	0.4286 (3)	0.1587 (2)	0.0336 (5)
C14	1.1232 (2)	0.3780 (3)	0.0786 (2)	0.0330 (5)
C15	1.0344 (2)	0.2887 (3)	0.02683 (14)	0.0260 (5)
C16	1.0244 (2)	0.2245 (3)	-0.0552 (2)	0.0331 (5)
C17	0.9361 (2)	0.1383 (3)	-0.09833 (15)	0.0325 (5)
C18	0.8534 (2)	0.1125 (3)	-0.06299 (13)	0.0246 (5)
C19	0.9498 (2)	0.2563 (2)	0.05844 (13)	0.0211 (4)
C20	0.7595 (2)	0.0141 (3)	-0.1129 (2)	0.0351 (6)

Table 2. Selected geometric parameters (Å, °)

Mo—O4	1.721 (2)	Mo—O1	1.9878 (14)
Mo—O3	1.727 (2)	Mo—N1	2.411 (2)
Mo—O2	1.9717 (14)	Mo—N2	2.492 (2)
O4—Mo—O3	105.49 (8)	O2—Mo—N1	86.20 (6)
O4—Mo—O2	94.84 (7)	O1—Mo—N1	73.74 (6)
O3—Mo—O2	102.15 (7)	O4—Mo—N2	164.77 (7)
O4—Mo—O1	103.14 (7)	O3—Mo—N2	86.12 (7)
O3—Mo—O1	92.86 (7)	O2—Mo—N2	72.73 (6)
O2—Mo—O1	152.61 (6)	O1—Mo—N2	85.75 (6)
O4—Mo—N1	89.11 (7)	N1—Mo—N2	81.46 (6)
O3—Mo—N1	162.29 (7)		

Data were collected using a Siemens CCD SMART System fitted with a low-temperature attachment.

Data collection: *ASTRO* (Siemens, 1995). Cell refinement: *SAINT* (Siemens, 1995). Data reduction: *SAINT*. Program(s) used to solve structure: *SHELXTL/PC* (Sheldrick, 1990). Program(s) used to refine structure: *SHELXL93* (Sheldrick, 1993). Molecular graphics: *SHELXTL/PC*. Software used to prepare material for publication: *SHELXL93*. Geometrical calculations: *PARST* (Nardelli, 1983).

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Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: MU1231). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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Bis[4-(4-dimethylaminostyryl)-N-methylpyridinium] Bis[maleonitriledithiolato(2-)-S,S']nickelate(II)

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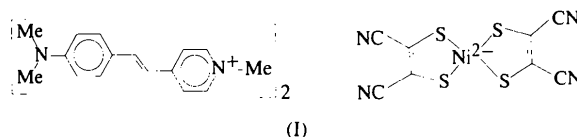
Abstract

In the title salt, (C₁₆H₁₉N₂)₂[Ni(C₄N₂S₂)₂], the bis-[maleonitriledithiolato(2-)-S,S']nickelate(II) anion and the two 4-(4-dimethylaminostyryl)-N-methylpyridinium cations are individually planar. The plane of the anion bisects the angle between the planes of the two independent cations.

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Comment

Salts of metal dithiolate complex anions, $[M(\text{mnt})_2]^{n-}$ [$M = \text{Ni}, \text{Zn}, \text{etc.}; \text{mnt} = \text{maleonitriledithiolate}(2-)$], with a variety of cations are found to possess interesting magnetic, electrical and optical properties (Manoharan, Noordik, de Boer & Keijzers, 1981; Clemenson, 1990). As part of our work on the synthesis and characterization of such complexes (Shan, Zhang, You, Fun & Sivakumar, 1995), we report the structure determination of the title compound, (I).



Bond lengths and angles in the anion and cations are normal. The Ni atom has square-planar coordination and the NiS_4 chromophore is planar. Unlike other complexes of this type where the Ni atom occupies an inversion centre which relates pairs of adjacent cations, the asymmetric unit comprises an anion and two adjacent cations which have their longest molecular axes roughly parallel (Fig. 1). The anion bisects the angle between the planes of the independent cations, with a dihedral angle of $76.41(4)^\circ$ between the planes of the anion and cation *A* and an angle of $76.88(3)^\circ$ between those of the anion and cation *B*; the dihedral angle between the planes of cations *A* and *B* is $153.29(5)^\circ$. There are no unusually short interionic contacts in this structure.

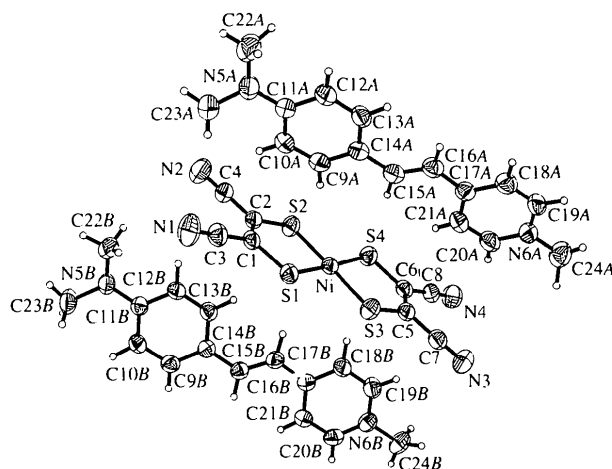


Fig. 1. A 50% displacement ellipsoid plot of (I) showing the atomic numbering scheme.

Experimental

The title salt was synthesized by the addition of an alcoholic solution of the pyridinium cation (as its iodide salt) to a solution of $(\text{NBu}_4)_2[\text{Ni}(\text{mnt})_2]$. Single crystals were obtained by recrystallization from dimethylformamide.

Crystal data

$(\text{C}_{16}\text{H}_{19}\text{N}_2)_2[\text{Ni}(\text{C}_4\text{N}_2\text{S}_2)_2]$
 $M_r = 817.73$
 Triclinic
 $P\bar{1}$
 $a = 7.438(1) \text{ \AA}$
 $b = 15.332(2) \text{ \AA}$
 $c = 17.722(3) \text{ \AA}$
 $\alpha = 103.36(1)^\circ$
 $\beta = 92.14(1)^\circ$
 $\gamma = 101.70(1)^\circ$
 $V = 1917.9(5) \text{ \AA}^3$
 $Z = 2$
 $D_x = 1.416 \text{ Mg m}^{-3}$
 D_m not measured

Mo $K\alpha$ radiation
 $\lambda = 0.71073 \text{ \AA}$
 Cell parameters from 25 reflections
 $\theta = 8-25^\circ$
 $\mu = 0.765 \text{ mm}^{-1}$
 $T = 293(2) \text{ K}$
 Plate
 $0.60 \times 0.42 \times 0.12 \text{ mm}$
 Black

Data collection

Siemens P4 diffractometer
 $\theta/2\theta$ scans
 Absorption correction:
 ψ scans (XSCANS;
 Siemens, 1994)
 $T_{\min} = 0.823$, $T_{\max} = 0.977$
 9967 measured reflections
 8120 independent reflections
 5642 observed reflections
 $[I > 2\sigma(I)]$

$R_{\text{int}} = 0.021$
 $\theta_{\text{max}} = 27.5^\circ$
 $h = -1 \rightarrow 9$
 $k = -19 \rightarrow 19$
 $l = -23 \rightarrow 23$
 3 standard reflections monitored every 97 reflections
 intensity decay: $<3\%$

Refinement

Refinement on F^2
 $R(F) = 0.0368$
 $wR(F^2) = 0.1059$
 $S = 0.934$
 8120 reflections
 630 parameters
 All H-atom parameters refined
 $w = 1/[\sigma^2(F_o^2) + (0.0620P)^2]$
 where $P = (F_o^2 + 2F_c^2)/3$

$(\Delta/\sigma)_{\text{max}} = -0.001$
 $\Delta\rho_{\text{max}} = 0.38 \text{ e \AA}^{-3}$
 $\Delta\rho_{\text{min}} = -0.26 \text{ e \AA}^{-3}$
 Extinction correction: none
 Atomic scattering factors from *International Tables for Crystallography* (1992), Vol. C, Tables 4.2.6.8 and 6.1.1.4)

Table 1. Fractional atomic coordinates and equivalent isotropic displacement parameters (\AA^2)

$$U_{\text{eq}} = (1/3)\sum_i \sum_j U_{ij} a_i^* a_j^* \mathbf{a}_i \cdot \mathbf{a}_j$$

	<i>x</i>	<i>y</i>	<i>z</i>	U_{eq}
Ni	0.20145 (4)	0.01576 (2)	0.253946 (14)	0.03621 (9)
S1	0.40326 (8)	0.14430 (4)	0.29683 (3)	0.04304 (14)
S2	-0.02857 (8)	0.08258 (4)	0.28050 (3)	0.04676 (14)
S3	0.42859 (8)	-0.05420 (4)	0.23103 (4)	0.04805 (14)
S4	-0.00249 (8)	-0.11001 (4)	0.20687 (3)	0.04729 (15)
N1	0.4206 (4)	0.3955 (2)	0.3673 (2)	0.0787 (7)
N2	-0.1187 (4)	0.3180 (2)	0.3392 (2)	0.0741 (7)
N3	0.5056 (4)	-0.2927 (2)	0.16451 (14)	0.0676 (6)
N4	-0.0363 (3)	-0.3631 (2)	0.14397 (13)	0.0647 (6)
C1	0.2669 (3)	0.22441 (14)	0.31856 (11)	0.0397 (5)
C2	0.0807 (3)	0.19764 (15)	0.31075 (12)	0.0406 (5)
C3	0.3545 (4)	0.3193 (2)	0.34546 (14)	0.0518 (6)
C4	-0.0317 (4)	0.2636 (2)	0.32670 (13)	0.0484 (5)
C5	0.3159 (3)	-0.16793 (15)	0.19670 (11)	0.0412 (5)
C6	0.1291 (3)	-0.19216 (15)	0.18767 (11)	0.0412 (5)
C7	0.4225 (4)	-0.2366 (2)	0.17914 (13)	0.0480 (5)
C8	0.0361 (4)	-0.2868 (2)	0.16318 (12)	0.0468 (5)
N5A	0.2297 (4)	0.4324 (2)	0.10566 (12)	0.0677 (7)
N6A	0.2770 (3)	-0.28008 (14)	-0.09130 (11)	0.0490 (5)
C9A	0.1974 (4)	0.1937 (2)	0.11535 (13)	0.0505 (6)

C10A	0.1969 (4)	0.2853 (2)	0.13686 (13)	0.0508 (6)
C11A	0.2325 (3)	0.3410 (2)	0.08395 (13)	0.0474 (5)
C12A	0.2670 (4)	0.2979 (2)	0.00840 (13)	0.0500 (6)
C13A	0.2684 (3)	0.2058 (2)	-0.01183 (13)	0.0474 (5)
C14A	0.2343 (3)	0.1507 (2)	0.04111 (12)	0.0450 (5)
C15A	0.2346 (3)	0.0532 (2)	0.02316 (14)	0.0484 (5)
C16A	0.2683 (4)	0.0018 (2)	-0.04342 (14)	0.0502 (6)
C17A	0.2714 (3)	-0.0947 (2)	-0.05712 (12)	0.0438 (5)
C18A	0.3172 (4)	-0.1407 (2)	-0.12901 (14)	0.0519 (6)
C19A	0.3195 (4)	-0.2309 (2)	-0.14436 (14)	0.0528 (6)
C20A	0.2346 (4)	-0.2376 (2)	-0.02067 (14)	0.0543 (6)
C21A	0.2298 (4)	-0.1480 (2)	-0.00238 (14)	0.0521 (6)
C22A	0.2578 (7)	0.4893 (3)	0.0511 (2)	0.0779 (10)
C23A	0.2434 (7)	0.4809 (3)	0.1864 (2)	0.0784 (10)
C24A	0.2762 (6)	-0.3789 (2)	-0.1088 (2)	0.0718 (8)
N5B	0.1694 (3)	0.40742 (13)	0.61611 (11)	0.0531 (5)
N6B	0.3070 (3)	-0.29303 (13)	0.43527 (11)	0.0456 (4)
C9B	0.2612 (3)	0.1888 (2)	0.64186 (12)	0.0438 (5)
C10B	0.2402 (3)	0.2780 (2)	0.65959 (12)	0.0453 (5)
C11B	0.1963 (3)	0.31897 (15)	0.60023 (12)	0.0405 (5)
C12B	0.1766 (3)	0.2652 (2)	0.52332 (12)	0.0419 (5)
C13B	0.1969 (3)	0.1766 (2)	0.50690 (12)	0.0422 (5)
C14B	0.2389 (3)	0.13488 (15)	0.56573 (12)	0.0394 (5)
C15B	0.2602 (3)	0.0403 (2)	0.55064 (12)	0.0416 (5)
C16B	0.2395 (3)	-0.0195 (2)	0.48172 (13)	0.0421 (5)
C17B	0.2638 (3)	-0.11269 (15)	0.46800 (12)	0.0391 (4)
C18B	0.2369 (3)	-0.1682 (2)	0.39248 (12)	0.0466 (5)
C19B	0.2591 (4)	-0.2563 (2)	0.37714 (14)	0.0509 (6)
C20B	0.3333 (3)	-0.2416 (2)	0.50888 (14)	0.0507 (6)
C21B	0.3116 (4)	-0.1540 (2)	0.52662 (13)	0.0487 (6)
C22B	0.1659 (5)	0.4539 (2)	0.5536 (2)	0.0570 (7)
C23B	0.2061 (6)	0.4648 (2)	0.6948 (2)	0.0652 (8)
C24B	0.3320 (5)	-0.3885 (2)	0.4166 (2)	0.0620 (7)

Table 2. Selected geometric parameters (\AA , $^\circ$)

Anion			
Ni—S4	2.1658 (7)	N2—C4	1.143 (3)
Ni—S1	2.1766 (7)	N3—C7	1.146 (3)
Ni—S2	2.1787 (7)	N4—C8	1.150 (3)
Ni—S3	2.1805 (7)	C1—C2	1.355 (3)
S1—C1	1.732 (2)	C1—C3	1.429 (3)
S2—C2	1.735 (2)	C2—C4	1.424 (3)
S3—C5	1.730 (2)	C5—C6	1.357 (3)
S4—C6	1.728 (2)	C5—C7	1.428 (3)
N1—C3	1.140 (3)	C6—C8	1.432 (3)
S4—Ni—S1	177.48 (2)	S4—Ni—S3	92.22 (3)
S4—Ni—S2	86.92 (3)	S1—Ni—S3	88.64 (3)
S1—Ni—S2	92.31 (3)	S2—Ni—S3	177.64 (2)
Cation A			
N5—C11	1.370 (3)	Cation B	
N5—C22	1.440 (4)	N5—C11	1.377 (3)
N5—C23	1.442 (4)	N5—C22	1.450 (3)
N6—C19	1.344 (3)	N5—C23	1.450 (3)
N6—C20	1.351 (3)	N6—C19	1.352 (3)
N6—C24	1.473 (4)	N6—C20	1.343 (3)
C9—C10	1.369 (3)	N6—C24	1.477 (3)
C9—C14	1.393 (3)	C9—C10	1.374 (3)
C10—C11	1.405 (3)	C9—C14	1.394 (3)
C11—C12	1.407 (3)	C10—C11	1.404 (3)
C12—C13	1.376 (3)	C11—C12	1.406 (3)
C13—C14	1.399 (3)	C12—C13	1.363 (3)
C14—C15	1.455 (3)	C13—C14	1.399 (3)
C15—C16	1.322 (3)	C14—C15	1.454 (3)
C16—C17	1.447 (3)	C15—C16	1.329 (3)
C17—C18	1.398 (3)	C16—C17	1.443 (3)
C17—C21	1.411 (3)	C17—C18	1.393 (3)
C18—C19	1.349 (4)	C17—C21	1.405 (3)
C20—C21	1.346 (4)	C18—C19	1.359 (3)
		C20—C21	1.351 (3)

Data collection: XSCANS (Siemens, 1994). Cell refinement: XSCANS. Data reduction: XSCANS. Program(s) used to solve structure: *SHELXTL/PC* (Sheldrick, 1990) by direct methods. Program(s) used to refine structure: *SHELXL93* (Sheldrick, 1993). Molecular graphics: *SHELXTL/PC*. Software used to prepare material for publication: *SHELXL93*. Geometrical calculations: *PARST* (Nardelli, 1983).

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Lists of structure factors, anisotropic displacement parameters, H-atom coordinates and complete geometry have been deposited with the IUCr (Reference: MU1233). Copies may be obtained through The Managing Editor, International Union of Crystallography, 5 Abbey Square, Chester CH1 2HU, England.

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Bis(*N*-benzyl-2-hydroxy-1-naphthalde- iminato)nickel(II)

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Abstract

The crystal structure of the title compound, bis-[1-(benzyliminomethyl)-2-naphtholato-*N,O*]nickel(II), $[Ni(C_{18}H_{14}NO)_2]$, has been determined. Two bidentate Schiff base ligands coordinate to the Ni atom in a square-planar arrangement.